Searci	h Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/773,314	OTAKA ET AL.
Examiner	Art Unit
Tho G. Phan	2821

	SEARCHED			
Class	Subclass	Date	Examiner	
343	700ms,702 ,895	5/25/2005	TP	
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NO		)
	DATE	EXMR
inverted-F, chip antenna, substrate, dielectric, radiator, radiating	5/25/2005	TP
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